

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10595766	BEYER ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	CECILIA M JAISLE	1624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
514	264.11	1/15/2008	C. Jaisle
544	270	1/15/2008	C. Jaisle
514	264.11	5/19/2008	C. Jaisle
544	270	5/19/2008	C. Jaisle

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
STN & <sup>A</sup> Inventor Names searched by STIC	1/15/2008	C. Jaisle

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
514	264.11	5/19/2008	C. Jaisle
544	270	5/19/2008	C. Jaisle